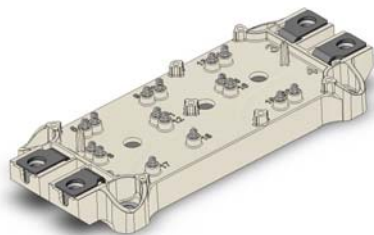


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SEMiX[®] 3s

SPT IGBT Modules

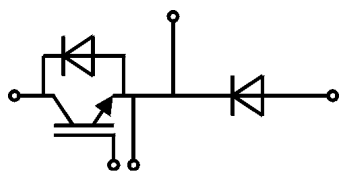
SEMiX553GAR128Ds

Features

- Homogeneous Si
- SPT = Soft-Punch-Through technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

Typical Applications*

- AC inverter drives
- UPS
- Electronic welders up to 20 kHz

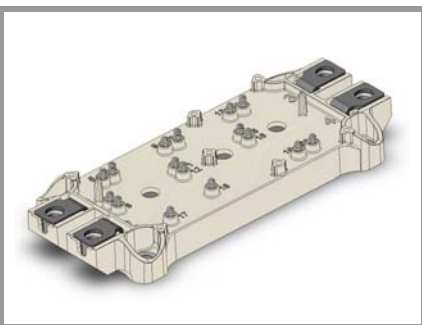


GAR

Absolute Maximum Ratings					
Symbol	Conditions		Values	Unit	
IGBT					
V_{CES}			1200	V	
I_C	$T_j = 150\text{ °C}$	$T_c = 25\text{ °C}$	533	A	
		$T_c = 80\text{ °C}$	379	A	
I_{Cnom}			300	A	
I_{CRM}	$I_{CRM} = 2 \times I_{Cnom}$		600	A	
V_{GES}			-20 ... 20	V	
t_{psc}	$V_{CC} = 600\text{ V}$ $V_{GE} \leq 20\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_j = 125\text{ °C}$	10		μs
T_j			-40 ... 150	$^{\circ}\text{C}$	
Inverse diode					
I_F	$T_j = 150\text{ °C}$	$T_c = 25\text{ °C}$	421	A	
		$T_c = 80\text{ °C}$	289	A	
I_{Fnom}			300	A	
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		600	A	
I_{FSM}	$t_p = 10\text{ ms, sin } 180^{\circ}, T_j = 25\text{ °C}$		2300	A	
T_j			-40 ... 150	$^{\circ}\text{C}$	
Freewheeling diode					
I_F	$T_j = 150\text{ °C}$	$T_c = 25\text{ °C}$	521	A	
		$T_c = 80\text{ °C}$	347	A	
I_{Fnom}			300	A	
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		600	A	
I_{FSM}	$t_p = 10\text{ ms, sin } 180^{\circ}, T_j = 25\text{ °C}$		2300	A	
T_j			-40 ... 150	$^{\circ}\text{C}$	
Module					
$I_{t(RMS)}$			600	A	
T_{stg}			-40 ... 125	$^{\circ}\text{C}$	
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$		4000	V	

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
$V_{CE(sat)}$	$I_C = 300\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25\text{ °C}$	1.9	2.35		V
		$T_j = 125\text{ °C}$	2.1	2.55		V
V_{CE0}		$T_j = 25\text{ °C}$	1	1.15		V
		$T_j = 125\text{ °C}$	0.9	1.05		V
r_{CE}	$V_{GE} = 15\text{ V}$	$T_j = 25\text{ °C}$	3.0	4.0		$\text{m}\Omega$
		$T_j = 125\text{ °C}$	4.0	5.0		$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 12\text{ mA}$		4.5	5	6.5	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25\text{ °C}$	0.1	0.3		mA
		$T_j = 125\text{ °C}$				mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	28.3			nF
C_{oes}		$f = 1\text{ MHz}$	1.86			nF
C_{res}		$f = 1\text{ MHz}$	1.17			nF
Q_G	$V_{GE} = -8\text{ V...} + 15\text{ V}$		2880			nC
R_{Gint}	$T_j = 25\text{ °C}$		1.33			Ω

SEMiX553GAR128Ds



SEMiX[®] 3s

SPT IGBT Modules

SEMiX553GAR128Ds

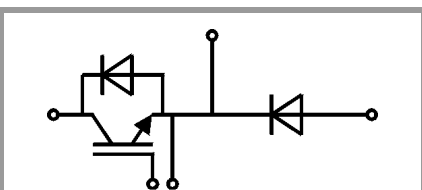
Features

- Homogeneous Si
- SPT = Soft-Punch-Through technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

Typical Applications*

- AC inverter drives
- UPS
- Electronic welders up to 20 kHz

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 125\text{ °C}$		185		ns
t_r	$I_C = 300\text{ A}$	$T_j = 125\text{ °C}$		65		ns
E_{on}	$R_{G\ on} = 3\ \Omega$	$T_j = 125\text{ °C}$		27		mJ
$t_{d(off)}$	$R_{G\ off} = 3\ \Omega$	$T_j = 125\text{ °C}$		635		ns
t_f		$T_j = 125\text{ °C}$		80		ns
E_{off}		$T_j = 125\text{ °C}$		33		mJ
$R_{th(j-c)}$	per IGBT				0.061	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 300\text{ A}$	$T_j = 25\text{ °C}$		2.0	2.50	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 125\text{ °C}$		1.8	2.3	V
V_{F0}		$T_j = 25\text{ °C}$	0.75	1.1	1.45	V
		$T_j = 125\text{ °C}$	0.5	0.85	1.2	V
r_F		$T_j = 25\text{ °C}$	2.5	3.0	3.5	m Ω
		$T_j = 125\text{ °C}$	2.7	3.2	3.7	m Ω
I_{RRM}	$I_F = 300\text{ A}$	$T_j = 125\text{ °C}$		325		A
Q_{rr}	$di/dt_{off} = 5400\text{ A}/\mu\text{s}$	$T_j = 125\text{ °C}$		46		μC
E_{rr}	$V_{GE} = -15\text{ V}$ $V_{CC} = 600\text{ V}$	$T_j = 125\text{ °C}$		17		mJ
$R_{th(j-c)}$	per diode				0.11	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 300\text{ A}$	$T_j = 25\text{ °C}$		2.0	2.5	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 125\text{ °C}$		1.8	2.3	V
V_{F0}		$T_j = 25\text{ °C}$	0.75	1.1	1.45	V
		$T_j = 125\text{ °C}$	0.5	0.85	1.2	V
r_F		$T_j = 25\text{ °C}$	2.5	3.0	3.5	m Ω
		$T_j = 125\text{ °C}$	2.7	3.2	3.7	m Ω
I_{RRM}	$I_F = 300\text{ A}$	$T_j = 125\text{ °C}$		325		A
Q_{rr}	$di/dt_{off} = 5400\text{ A}/\mu\text{s}$	$T_j = 125\text{ °C}$		46		μC
E_{rr}	$V_{GE} = -15\text{ V}$ $V_{CC} = 600\text{ V}$	$T_j = 125\text{ °C}$		17		mJ
$R_{th(j-c)}$	per diode				0.11	K/W
Module						
L_{CE}				20		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_C = 25\text{ °C}$		0.7		m Ω
		$T_C = 125\text{ °C}$		1		m Ω
$R_{th(c-s)}$	per module			0.04		K/W
M_s	to heat sink (M5)		3		5	Nm
M_t		to terminals (M6)	2.5		5	Nm
						Nm
w					300	g
Temperatur Sensor						
R_{100}	$T_C = 100\text{ °C}$ ($R_{25} = 5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R_{(T)} = R_{100} \exp[B_{100/125}(1/T - 1/T_{100})]$; $T[\text{K}]$;			$3550 \pm 2\%$		K



GAR

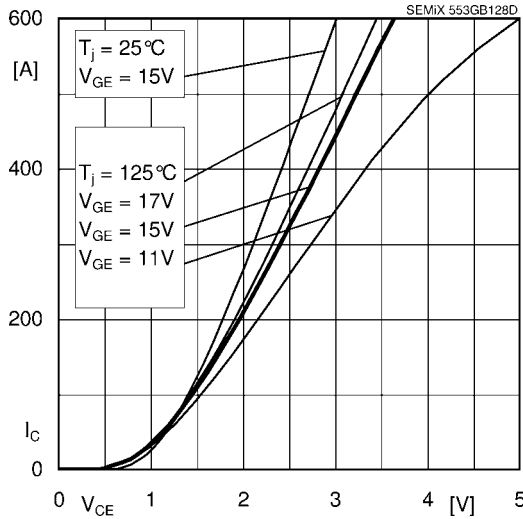


Fig. 1: Typ. output characteristic, inclusive $R_{CC'+EE'}$

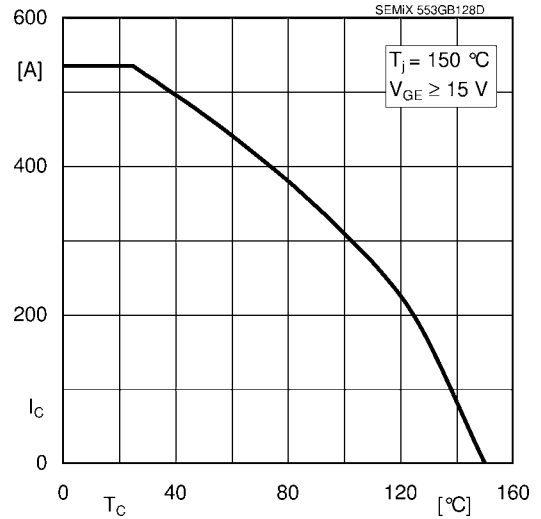


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

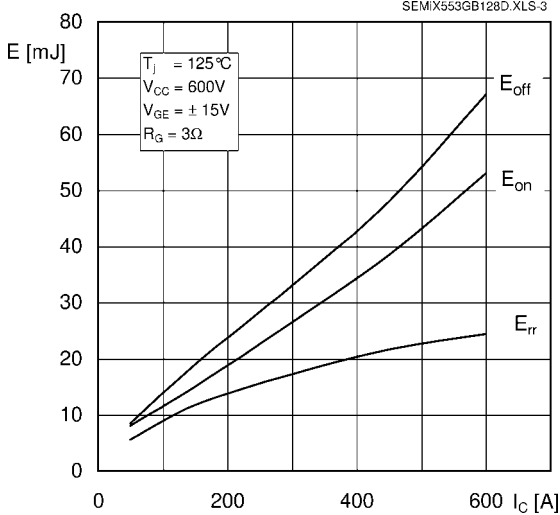


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

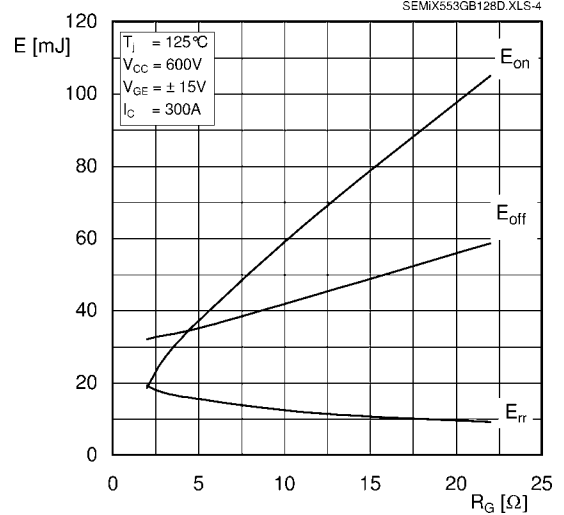


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

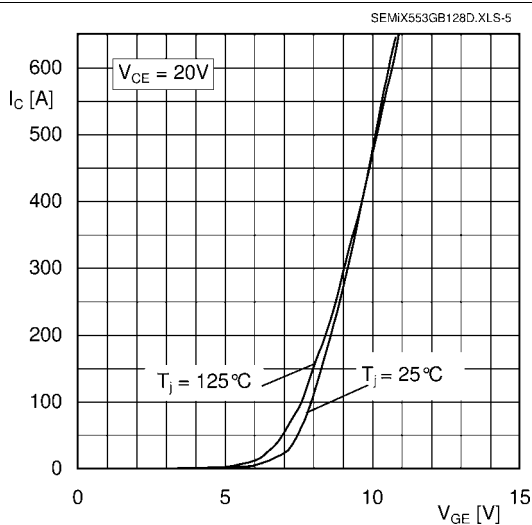


Fig. 5: Typ. transfer characteristic

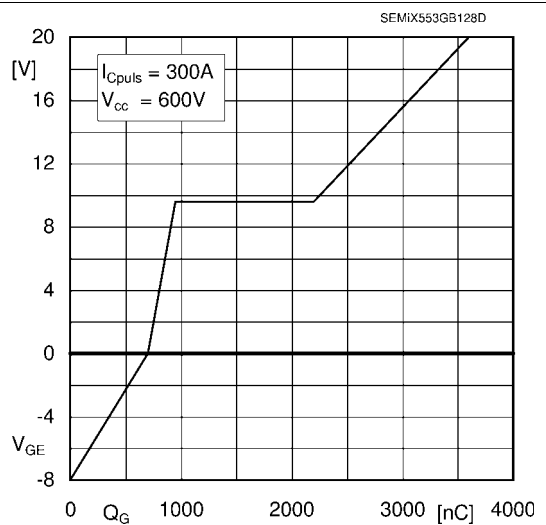


Fig. 6: Typ. gate charge characteristic

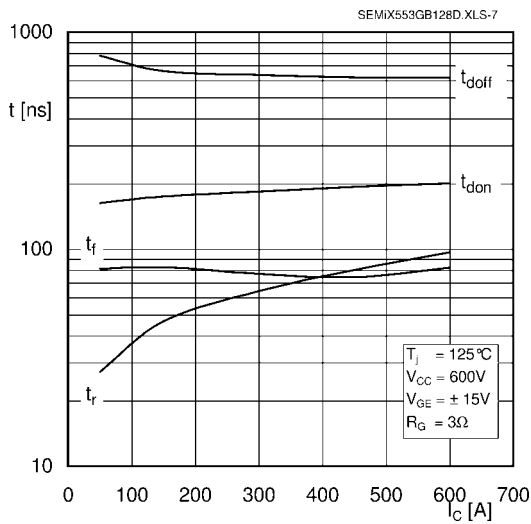


Fig. 7: Typ. switching times vs. I_C

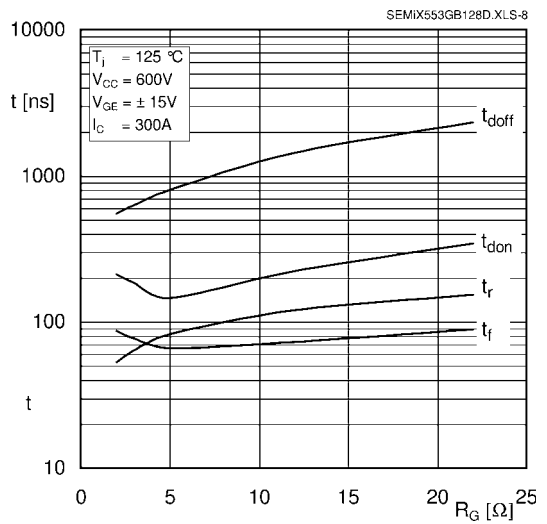


Fig. 8: Typ. switching times vs. gate resistor R_G

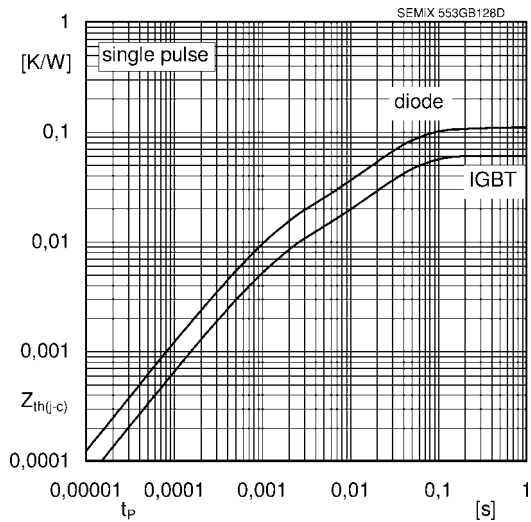


Fig. 9: Typ. transient thermal impedance

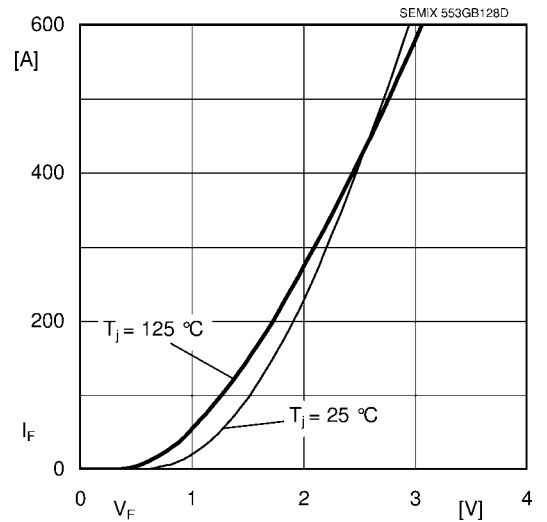


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC+EE'}$

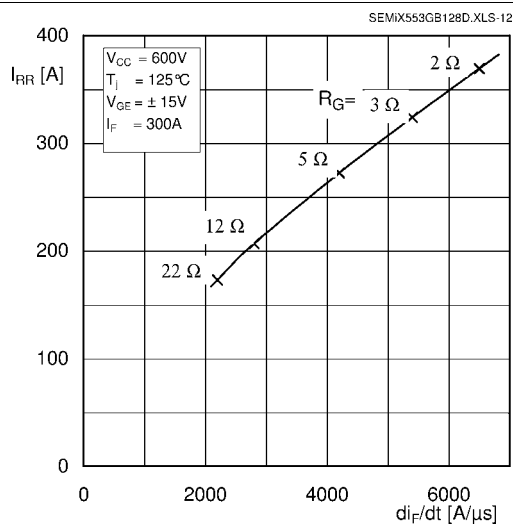


Fig. 11: Typ. CAL diode peak reverse recovery current

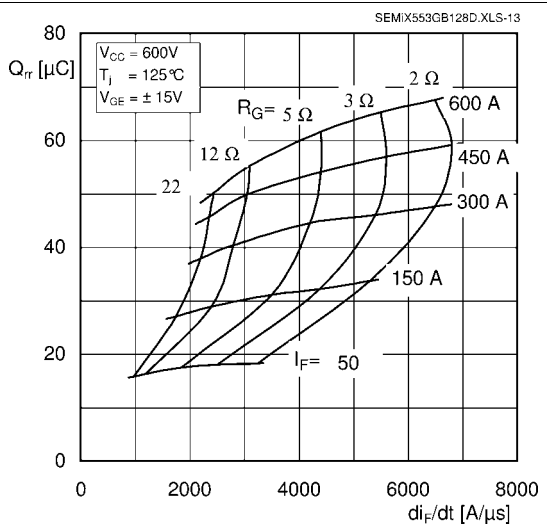


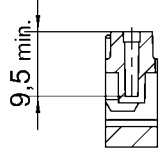
Fig. 12: Typ. CAL diode recovery charge

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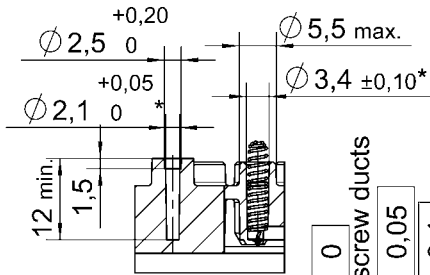
Case: SEMiX 3s

general tolerance ISO 2768-mK

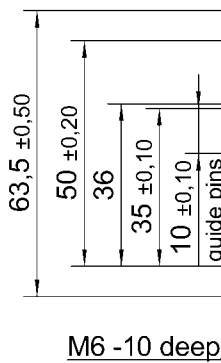
screw duct
(1x centre) :
H-H (1:1)



screw duct (6x)
spring duct (16x) :
A-A (1:1)

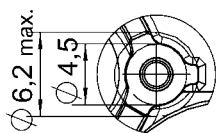


marking of terminals

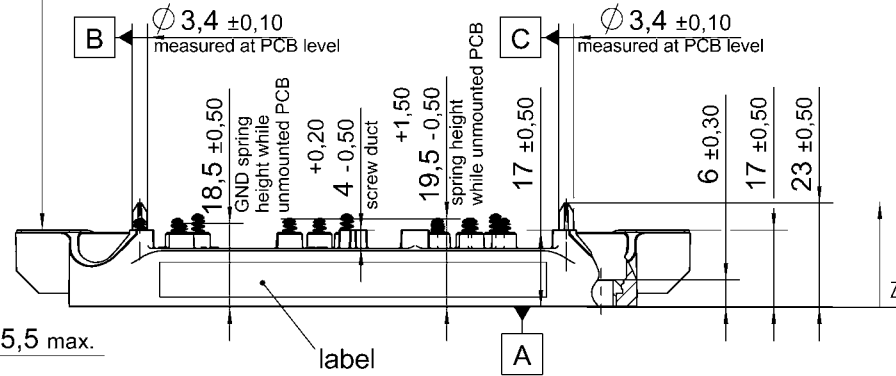


M6 -10 deep

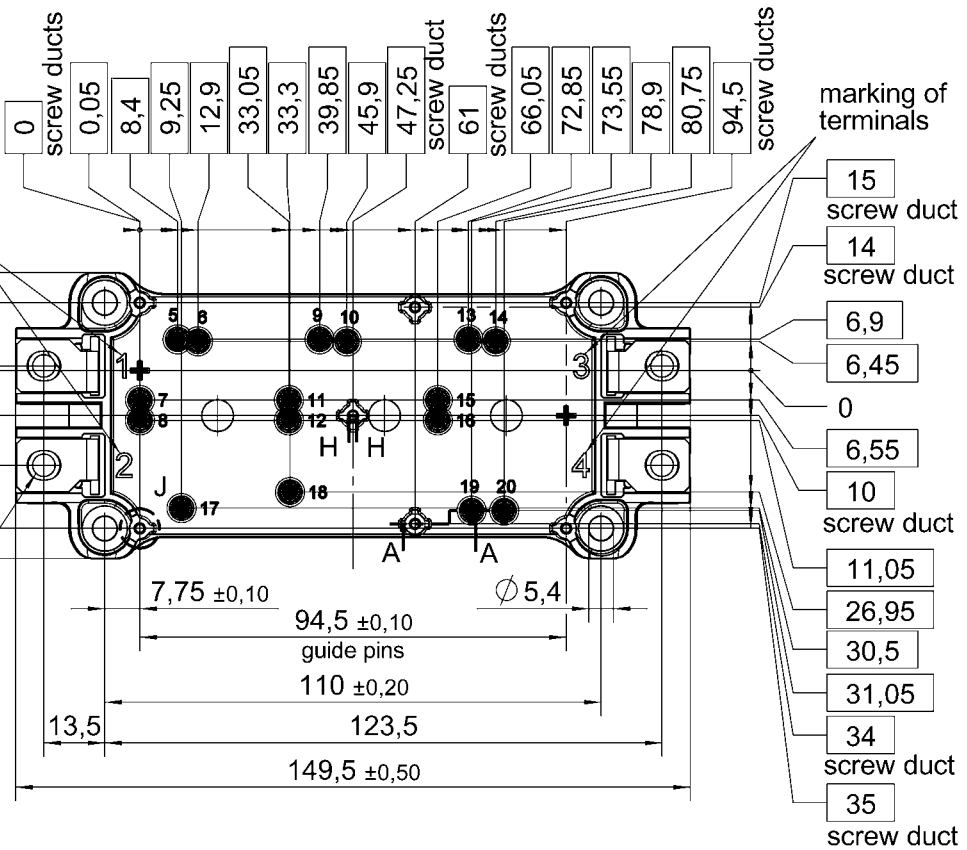
screw duct
top view (7x) :
J (2:1)



	0,3	connector 1-2 / 3-4
	0,2	each connector A



All measures in Z-direction
valid as mounted to heat sink

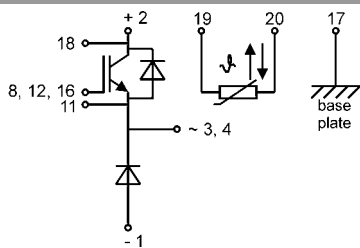


*screw ducts / spring ducts with $\phi \pm 0,2$ A B C

Rules for the contact PCB:

- holes guidepins = $\phi 4 \pm 0,1$ / position tolerance $\pm 0,1$
- spring landing pad = $\phi 3,5 \pm 0,2$ / position tolerance $\pm 0,2$

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spring configuration

SEMiX553GAR128Ds

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our personal.